

| | | | | |
|-----------------------------------|--|-------------------------|--|-------------|
| Notice of References Cited | | Application/Control No. | Applicant(s)/Patent Under Reexamination BEENAU ET AL. | |
| | | Examiner | Art Unit | Page 1 of 1 |
| U.S. PATENT DOCUMENTS | | | | |

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|------------------------|----------------|
| | A | US-6,601,759 | 08-2003 | Fife et al. | 235/375 |
| | B | US-2003/0173408 | 09-2003 | Mosher et al. | 235/492 |
| | C | US-6,446,862 | 09-2002 | Mann, W. Stephen G. | 235/380 |
| | D | US-H0,002,120 | 07-2005 | Cudlitz, Stephen | 235/382 |
| | E | US-2001/0036835 | 11-2001 | Leedom, Charles M. JR. | 455/509 |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| | | |
|---|---|---|
| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.